

## APPLICATION NOTE

MITSUBISHI&lt;IGBT MODULE&gt;

## Preliminary

CM1000DU-34NF

Pre.	J.Yamada	Rev	D	M. Kura
Apr.	M.Yamamoto Dec.14 '01			T. Furusawa 20-Oct-03

HIGH POWER SWITCHING USE

Notice : This is not a final specification. Some parametric limits are subject to change.

CM1000DU-34NF

- $I_C$  ..... 1000A
- $V_{CES}$  ..... 1700V
- Insulated Type
- 2-elements in a pack

## APPLICATION

General purpose inverters &amp; Servo controls, etc

ABSOLUTE MAXIMUM RATINGS ( $T_J = 25^\circ\text{C}$ )

Symbol	Item	Conditions	Ratings	Units	
$V_{CES}$	Collector-emitter voltage	G-E Short	1700	V	
$V_{GES}$	Gate-emitter voltage	C-E Short	$\pm 20$	V	
$I_C$	Collector current	$T_c = 104^\circ\text{C}$	1000	A	B
$I_{CM}$		Pulse ②	2000		
$I_E$ ①	Emitter current	$T_c = 25^\circ\text{C}$	1000	A	
$I_{EM}$ ①		Pulse ②	2000		
$P_C$ ③	Maximum collector dissipation	$T_c = 25^\circ\text{C}$	3900	W	B
$T_J$	Junction temperature		$-40 \sim +150$	$^\circ\text{C}$	D
$T_{stg}$	Storage temperature <sup>*3</sup>		$-40 \sim +125$	$^\circ\text{C}$	B
Viso	Isolation voltage	Main terminal to base plate, AC 1 min.	3500	V	C
—	Torque strength	Main terminal M6	3.5 ~ 4.5	N·m	
—	Torque strength	Mounting holes M6	3.5 ~ 4.5	N·m	
—	Weight	Typical value	1400	g	

ELECTRICAL CHARACTERISTICS ( $T_j = 25^\circ\text{C}$ )

Symbol	Item	Conditions	Min.	Typ.	Max.	Units	
$I_{CES}$	Collector cutoff current	$V_{CE}=V_{CES}, V_{GE}=0V$	—	—	1	mA	
$V_{GE(th)}$	Gate-emitter threshold voltage	$I_C=100mA, V_{CE}=10V$	6	7	8	V	[B]
$I_{GES}$	Gate leakage current	$V_{GE}=V_{GES}, V_{CE}=0V$	—	—	5	$\mu A$	[B]
$V_{CE(sat)}$ (chip)	Collector to emitter saturation voltage(without lead resistance)	$T_j=25^\circ\text{C}$ $I_C=1000A$	—	2.2	2.8	V	[B]
		$T_j=125^\circ\text{C}$ $V_{GE}=15V$ ④	—	2.45	—		[D]
$R(\text{lead})$	Module lead resistance	$I_C=1000A$ , terminal-chip	—	0.286	—	m $\Omega$	[A][B]
$C_{ies}$	Input capacitance	$V_{CE}=10V$	—	—	220	nF	[B]
$C_{oes}$	Output capacitance	$V_{GE}=0V$	—	—	25		
$C_{res}$	Reverse transfer capacitance		—	—	4.7		
$Q_g$	Total gate charge	$V_{CC}=1000V, I_C=1000A, V_{GE}=15V$	—	6000	—	nC	[B][D]
$t_{d(on)}$	Turn-on delay time	$V_{CC}=1000V, I_C=1000A$	—	—	600	ns	[B]
$t_r$	Turn-on rise time	$V_{GE1}=V_{GE2}=15V$	—	—	150		[B]
$t_{d(off)}$	Turn-off delay time	$R_G=0.47\Omega$ , Inductive load switching operation	—	—	900		[B]
$t_f$	Turn-off fall time		—	—	200		[B]
$t_{rr}$	Reverse recovery time	$I_E=1000A$	—	—	450	ns	[B]
$Q_{rr}$	Reverse recovery charge		—	90	—	$\mu C$	[B][D]
$V_{EC}$ ①	Emitter-collector voltage (without lead resistance)	$I_E=1000A, V_{GE}=0V$	—	2.3	3	V	[B]
$R_{th(j-c)Q}$	Thermal resistance*	IGBT part (1/2module)	—	—	0.032	$^\circ\text{C/W}$	[D]
$R_{th(j-c)R}$		FWDi part (1/2module)	—	—	0.053		
$R_{th(c-f)}$	Contact thermal resistance <sup>2</sup>	Case to fin, Thermal compound Applied (1/2module)	—	0.016	—		
$R_{th(j-c')Q}$	Thermal resistance*	Tc measured point is just under the chips(IGBT part)	—	—	0.014	$^\circ\text{C/W}$	
$R_{th(j-c')R}$		Tc measured point is just under the chips(FWDi part)	—	—	0.023		
$R_g$	External gate resistance		0.47	—	4.7	$\Omega$	[B]

\*1: Tc' measured point is just under the chips.

If you use this value,  $R_{th(f-a)}$  should be measured just under the chips.

\*2: Typical value is measured by using Shin-etsu Silicone "G-746".

\*3: Tc measured point is shown in page "3-3".

\*4: The operation temperature is restrained by the permission temperature of female connector.

①  $I_E, V_{EC}, t_{rr}$  &  $Q_{rr}$  represent characteristics of the anti-parallel, emitter to collector free-wheel diode (FWDi).② Pulse width and repetition rate should be such that the device junction temp. ( $T_j$ ) dose not exceed  $T_{jmax}$  rating.③ Junction temperature ( $T_j$ ) should not increase beyond  $150^\circ\text{C}$ .

④ Pulse width and repetition rate should be such as to cause neglible temperature rise.

**mitsubishi**  
**IGBT MODULE**  
**CM1000DU-34NF**  
 HIGH POWER SWITCHING USE

## OUTLINE DRAWING

Dimensions in mm

A,B HOUSING Type

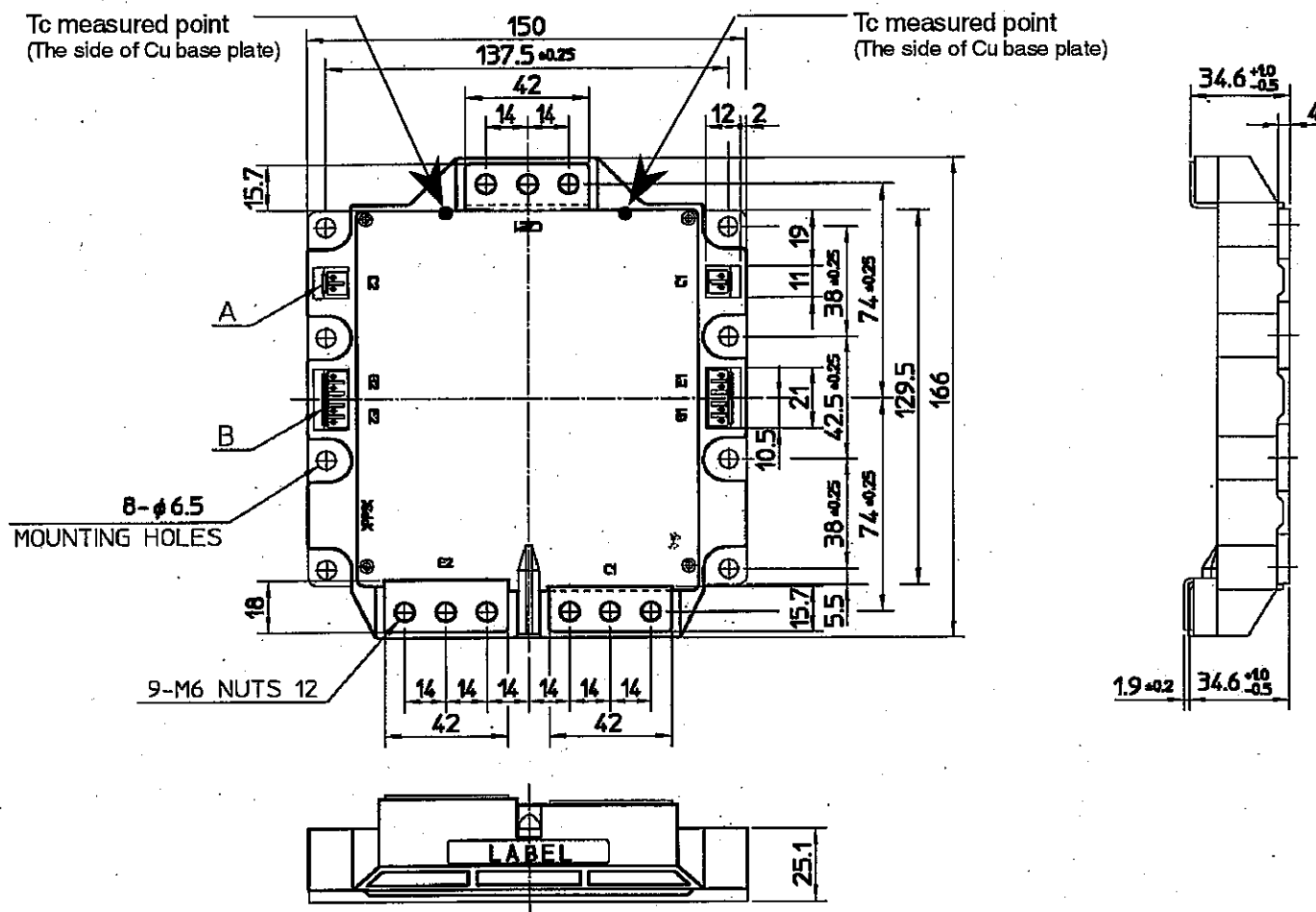
(J.S.T.Mfg.Co.,Ltd)

A : VHR-2N

B : VHR-5N

Tc measured point —  
(The side of Cu base plate)

- Tc measured point  
(The side of Cu base plate)



### CIRCUIT DIAGRAM

